

2829/8
Fetterman 7-17

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application

Applicant(s): H. Scott Fetterman et al.

Case: 7-17

Serial No.: 10/007,904

Filing Date: October 31, 2001

Group: 2829

Examiner: Evan T. Pert

Title: Stress Migration Test Structure
and Method Therefor

I hereby certify that this paper is being deposited on this date with the U.S. Postal Service as first class mail addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Signature: Laura M. Hanin

Date: June 25, 2003

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TECHNOLOGY CENTER 2800

AMENDMENT TRANSMITTAL

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Submitted herewith are the following documents relating to the above-identified patent application:

- (1) Amendment and Response to Office Action with enclosure(s);
- (2) Associate Power of Attorney; and
- (3) Change of Correspondence Address.

Please extend the period for response by one month to June 25, 2003. There is an additional claim fee of \$204 due in conjunction with the Amendment. Please charge **Ryan, Mason & Lewis Deposit Account No. 50-0762** the amount of \$314 (\$204 to cover the additional claim fee and \$110 to cover the one month extension fee). In the event of non-payment or improper payment of a required fee, the Commissioner is authorized to charge or to credit **Deposit Account No. 50-0762** as required to correct the error. A duplicate copy of this letter is enclosed.

Respectfully submitted,

Joseph B. Ryan
Attorney for Applicant(s)
Reg. No. 37,922
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90 Forest Avenue
Locust Valley, NY 11560
(516) 759-7517

Date: June 25, 2003



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AMENDMENT AND RESPONSE TO OFFICE ACTION

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the outstanding Office Action dated February 25, 2003, please amend the above-identified application as follows:

IN THE SPECIFICATION

Please replace the paragraph beginning on page 7, line 6, and ending on page 8, line 2, with the following rewritten paragraph:

--A combination of factors, not just the size of the metal runner alone, accounts for the ability of the stress migration test structure 10 to detect stress migration voids, and concomitantly permits an inference of the presence or absence of stress migration voids in other conductors similarly manufactured. The factors include the voltage across the resistance string, the voltage measurement resolution of the test hardware, the expected magnitude of impedance deviation from the ideal impedance expected in the presence of a stress migration void, the probability of finding a stress migration void in a length of metal runner between two adjacent taps, and the desired confidence that

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01 FC:125t 110.00 DA
02 FC:1202 36.00 DA
03 FC:1201 168.00 DA